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### **Understanding Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	300000
Total RAM Bits	21094400
Number of I/O	388
Number of Gates	-
Voltage - Supply	0.97V ~ 1.08V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/mpf300ts-fcg784i">https://www.e-xfl.com/product-detail/microchip-technology/mpf300ts-fcg784i</a>

The maximum overshoot duration is specified as a high-time percentage over the lifetime of the device. A DC signal is equivalent to 100% of the duty-cycle.

The following table shows the maximum AC input voltage ( $V_{IN}$ ) overshoot duration for HSIO.

**Table 6 • Maximum Overshoot During Transitions for HSIO**

AC ( $V_{IN}$ ) Overshoot Duration as % at $T_J = 100^\circ\text{C}$	Condition (V)
100	1.8
100	1.85
100	1.9
100	1.95
100	2
100	2.05
100	2.1
100	2.15
100	2.2
90	2.25
30	2.3
7.5	2.35
1.9	2.4

**Note:** Overshoot level is for VDDI at 1.8 V.

The following table shows the maximum AC input voltage ( $V_{IN}$ ) undershoot duration for HSIO.

**Table 7 • Maximum Undershoot During Transitions for HSIO**

AC ( $V_{IN}$ ) Undershoot Duration as % at $T_J = 100^\circ\text{C}$	Condition (V)
100	-0.05
100	-0.1
100	-0.15
100	-0.2
100	-0.25
100	-0.3
100	-0.35
100	-0.4
44	-0.45
14	-0.5
4.8	-0.55
1.6	-0.6

The following table shows the maximum AC input voltage ( $V_{IN}$ ) overshoot duration for GPIO.

I/O Standard	Bank Type	VICM RANGE Libero Setting	V <sub>ICM<sup>1,3</sup></sub> Min (V)	V <sub>ICM<sup>1,3</sup></sub> Typ (V)	V <sub>ICM<sup>1,3</sup></sub> Max (V)	V <sub>ID<sup>2</sup></sub> Min (V)	V <sub>ID</sub> Typ (V)	V <sub>ID</sub> Max (V)
LVDS18	HSIO	Low	0.05	0.4	0.8	0.1	0.35	0.6
		Mid (default)	0.6	1.25	1.65	0.1	0.35	0.6
LCMDS33	GPIO	Low	0.05	0.4	0.8	0.1	0.35	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.35	0.6
LCMDS18	HSIO	Low	0.05	0.4	0.8	0.1	0.35	0.6
		Mid (default)	0.6	1.25	1.65	0.1	0.35	0.6
LCMDS25	GPIO	Low	0.05	0.4	0.8	0.1	0.35	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.35	0.6
RSDS33	GPIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.2	0.6
RSDS25	GPIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.2	0.6
RSDS18 <sup>5</sup>	HSIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	1.25	1.65	0.1	0.2	0.6
MINILVDS33	GPIO	Low	0.05	0.4	0.8	0.1	0.3	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.3	0.6
MINILVDS25	GPIO	Low	0.05	0.4	0.8	0.1	0.3	0.6
		Mid (default)	0.6	1.25	2.35	0.1	0.3	0.6
MINILVDS18 <sup>5</sup>	HSIO	Low	0.05	0.4	0.8	0.1	0.3	0.6
		Mid (default)	0.6	1.25	1.65	0.1	0.3	0.6
SUBLVDS33	GPIO	Low	0.05	0.4	0.8	0.1	0.15	0.3
		Mid (default)	0.6	0.9	2.35	0.1	0.15	0.3
SUBLVDS25	GPIO	Low	0.05	0.4	0.8	0.1	0.15	0.3
		Mid (default)	0.6	0.9	2.35	0.1	0.15	0.3
SUBLVDS18 <sup>5</sup>	HSIO	Low	0.05	0.4	0.8	0.1	0.15	0.3
		Mid (default)	0.6	0.9	1.65	0.1	0.15	0.3
PPDS33	GPIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	0.8	2.35	0.1	0.2	0.6
PPDS25	GPIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	0.8	2.35	0.1	0.2	0.6
PPDS18 <sup>5</sup>	HSIO	Low	0.05	0.4	0.8	0.1	0.2	0.6
		Mid (default)	0.6	0.8	1.65	0.1	0.2	0.6
SLVS33 <sup>6</sup>	GPIO	Low	0.05	0.2	0.8	0.1	0.2	0.3
		Mid (default)	0.6	1.25	2.35	0.1	0.2	0.3
SLVS25 <sup>6</sup>	GPIO	Low	0.05	0.2	0.8	0.1	0.2	0.3
		Mid (default)	0.6	1.25	2.35	0.1	0.2	0.3
SLVS18 <sup>5</sup>	HSIO	Low	0.05	0.4	0.8	0.1	0.2	0.3
		Mid (default)	0.6	1.00	1.65	0.1	0.2	0.3
HCSL33 <sup>6</sup>	GPIO	Low	0.05	0.35	0.8	0.1	0.55	1.1
		Mid (default)	0.6	1.25	2.35	0.1	0.55	1.1

I/O Standard	Bank Type	V <sub>O<sub>CM</sub></sub> <sup>1</sup> Min (V)	V <sub>O<sub>CM</sub></sub> Typ (V)	V <sub>O<sub>CM</sub></sub> Max (V)	V <sub>O<sub>D</sub></sub> <sup>2</sup> Min (V)	V <sub>O<sub>D</sub></sub> <sup>2</sup> Typ (V)	V <sub>O<sub>D</sub></sub> <sup>2</sup> Max (V)
MILVDS25 <sup>3</sup>	GPIO		1.25		0.396	0.442	0.453
LVPECLE33 <sup>3</sup>	GPIO		1.65		0.664	0.722	0.755
MIPIE25 <sup>3</sup>	GPIO		0.25		0.1	0.22	0.3

1. V<sub>O<sub>CM</sub></sub> is the output common mode voltage.
2. V<sub>O<sub>D</sub></sub> is the output differential voltage.
3. Emulated output only.

### 6.3.3 Complementary Differential DC Input and Output Levels

The following tables list the complementary differential DC I/O levels.

**Table 16 • Complementary Differential DC Input Levels**

I/O Standard	V <sub>DDI</sub> Min (V)	V <sub>DDI</sub> Typ (V)	V <sub>DDI</sub> Max (V)	V <sub>I<sub>CM</sub></sub> <sup>1,3</sup> Min (V)	V <sub>I<sub>CM</sub></sub> <sup>1,3</sup> Typ (V)	V <sub>I<sub>CM</sub></sub> <sup>1,3</sup> Max (V)	V <sub>I<sub>D</sub></sub> <sup>2</sup> Min (V)	V <sub>I<sub>D</sub></sub> Max (V)
SSTL25I	2.375	2.5	2.625	1.164	1.250	1.339	0.1	
SSTL25II	2.375	2.5	2.625	1.164	1.250	1.339	0.1	
SSTL18I	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
SSTL18II	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
SSTL15I	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
SSTL15II	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
SSTL135I	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
SSTL135II	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL15I	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
HSTL15II	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
HSTL135I	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL135II	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL12I	1.14	1.2	1.26	0.559	0.600	0.643	0.1	
HSUL18I	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
HSUL18II	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
HSUL12I	1.14	1.2	1.26	0.559	0.600	0.643	0.1	
POD12I	1.14	1.2	1.26	0.787	0.840	0.895	0.1	
POD12II	1.14	1.2	1.26	0.787	0.840	0.895	0.1	

1. V<sub>I<sub>CM</sub></sub> is the input common mode voltage.
2. V<sub>I<sub>D</sub></sub> is the input differential voltage.
3. V<sub>I<sub>CM</sub></sub> rules are as follows:
  - a. V<sub>I<sub>CM</sub></sub> must be less than V<sub>DDI</sub> - 0.4V;
  - b. V<sub>I<sub>CM</sub></sub> + V<sub>I<sub>D</sub></sub>/2 must be < V<sub>DDI</sub> + 0.4 V;
  - c. V<sub>I<sub>CM</sub></sub> - V<sub>I<sub>D</sub></sub>/2 must be > V<sub>SS</sub> - 0.3 V.

Min (%)	Typ	Max (%)	Unit	Condition
-20	60	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	120	20	Ω	$V_{DDI} = 1.2 \text{ V}$

**Note:** Thevenin impedance is calculated based on independent P and N as measured at 50% of  $V_{DDI}$ . For 50 Ω/75 Ω/150 Ω cases, nearest supported values of 40 Ω/60 Ω/120 Ω are used.

**Table 19 • Single-Ended Termination to VDDI (Internal Parallel Termination to VDDI)**

Min (%)	Typ	Max (%)	Unit	Condition
-20	34	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	40	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	48	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	60	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	80	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	120	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	240	20	Ω	$V_{DDI} = 1.2 \text{ V}$

**Note:** Measured at 80% of  $V_{DDI}$ .

**Table 20 • Single-Ended Termination to VSS (Internal Parallel Termination to VSS)**

Min (%)	Typ	Max (%)	Unit	Condition
-20	120	20	Ω	$V_{DDI} = 1.8 \text{ V}/1.5 \text{ V}$
-20	240	20	Ω	$V_{DDI} = 1.8 \text{ V}/1.5 \text{ V}$
-20	120	20	Ω	$V_{DDI} = 1.2 \text{ V}$
-20	240	20	Ω	$V_{DDI} = 1.2 \text{ V}$

**Note:** Measured at 50% of  $V_{DDI}$ .

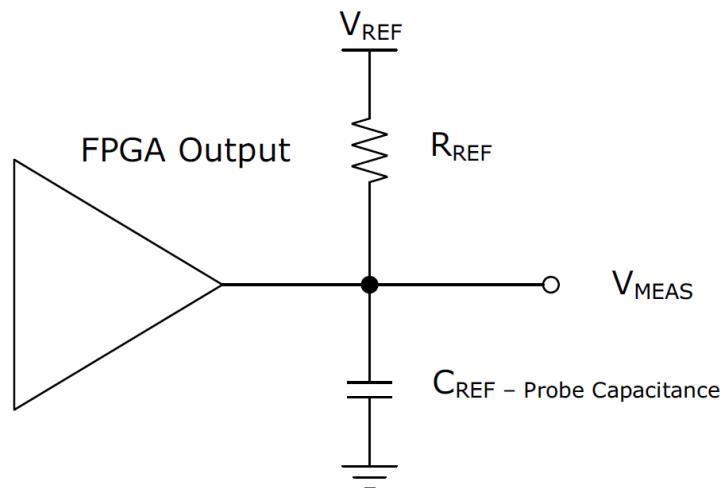
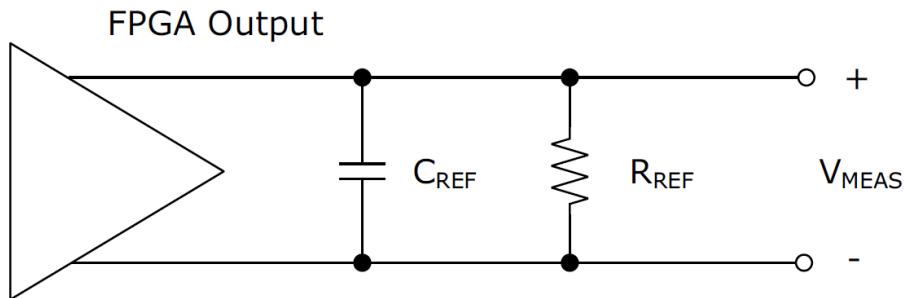
### 6.3.5 GPIO On-Die Termination

The following table lists the on-die termination calibration accuracy specifications for GPIO bank.

**Table 21 • On-Die Termination Calibration Accuracy Specifications for GPIO Bank**

Parameter	Description	Min (%)	Typ	Max (%)	Unit	Condition
Differential termination <sup>1</sup>	Internal differential termination	-20	100	20	Ω	$V_{ICM} < 0.8 \text{ V}$
		-20	100	40	Ω	$0.6 \text{ V} < V_{ICM} < 1.65 \text{ V}$
		-20	100	80	Ω	$1.4 \text{ V} < V_{ICM}$
Single-ended thevenin termination <sup>2,3</sup>	Internal parallel thevenin termination	-40	50	20	Ω	$V_{DDI} = 1.8 \text{ V}/1.5 \text{ V}$
		-40	75	20	Ω	$V_{DDI} = 1.8 \text{ V}$
		-40	150	20	Ω	$V_{DDI} = 1.8 \text{ V}$
		-20	20	20	Ω	$V_{DDI} = 1.5 \text{ V}$
		-20	30	20	Ω	$V_{DDI} = 1.5 \text{ V}$
		-20	40	20	Ω	$V_{DDI} = 1.5 \text{ V}$
		-20	60	20	Ω	$V_{DDI} = 1.5 \text{ V}$
		-20	120	20	Ω	$V_{DDI} = 1.5 \text{ V}$

Standard	Description	V <sub>L</sub> <sup>1</sup>	V <sub>H</sub> <sup>1</sup>	V <sub>ld</sub> <sup>2</sup>	V <sub>ICM</sub> <sup>2</sup>	V <sub>MEAS</sub> <sup>3,4</sup>	V <sub>REF</sub> <sup>1,5</sup>	Unit
HSUL18I	HSUL 1.8 V Class I	V <sub>REF</sub> – 0.54	V <sub>REF</sub> + 0.54			V <sub>REF</sub>	0.90	V
HSUL18II	HSUL 1.8 V Class II	V <sub>REF</sub> – 0.54	V <sub>REF</sub> + 0.54			V <sub>REF</sub>	0.90	V
HSUL12	HSUL 1.2 V	V <sub>REF</sub> – .22	V <sub>REF</sub> + .22			V <sub>REF</sub>	0.60	V
POD12I	Pseudo open drain (POD) logic 1.2 V Class I	V <sub>REF</sub> – .15	V <sub>REF</sub> + .15			V <sub>REF</sub>	0.84	V
POD12II	POD 1.2 V Class II	V <sub>REF</sub> – .15	V <sub>REF</sub> + .15			V <sub>REF</sub>	0.84	V
LVDS33	Low-voltage differential signaling (LVDS) 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
LVDS25	LVDS 2.5 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
LVDS18	LVDS 1.8 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.900	0		V
RSDS33	RSDS 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
RSDS25	RSDS 2.5 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
RSDS18	RSDS 1.8 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
MINILVDS33	Mini-LVDS 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
MINILVDS25	Mini-LVDS 2.5 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
MINILVDS18	Mini-LVDS 1.8 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	1.250	0		V
SUBLVDS33	Sub-LVDS 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.900	0		V
SUBLVDS25	Sub-LVDS 2.5 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.900	0		V
SUBLVDS18	Sub-LVDS 1.8 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.900	0		V
PPDS33	Point-to-point differential signaling 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.800	0		V
PPDS25	PPDS 2.5 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.800	0		V
PPDS18	PPDS 1.8 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.800	0		V
SLVS33	Scalable low- voltage signaling 3.3 V	V <sub>ICM</sub> – .125	V <sub>ICM</sub> + .125	0.250	0.200	0		V

**Figure 1 • Output Delay Measurement—Single-Ended Test Setup****Figure 2 • Output Delay Measurement—Differential Test Setup**

### 7.1.3 Input Buffer Speed

The following tables provide information about input buffer speed.

**Table 24 • HSIO Maximum Input Buffer Speed**

Standard	STD	-1	Unit
LVDS18	1250	1250	Mbps
RSDS18	800	800	Mbps
MINILVDS18	800	800	Mbps
SUBLVDS18	800	800	Mbps
PPDS18	800	800	Mbps
SLVS18	800	800	Mbps
SSTL18I	800	1066	Mbps
SSTL18II	800	1066	Mbps
SSTL15I	1066	1333	Mbps
SSTL15II	1066	1333	Mbps
SSTL135I	1066	1333	Mbps
SSTL135II	1066	1333	Mbps

Standard	STD	-1	Unit
HSTL15I	900	1100	Mbps
HSTL15II	900	1100	Mbps
HSTL135I	1066	1066	Mbps
HSTL135II	1066	1066	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
HSUL12	1066	1333	Mbps
HSTL12	1066	1266	Mbps
POD12I	1333	1600	Mbps
POD12II	1333	1600	Mbps
LVCMOS18 (12 mA)	500	500	Mbps
LVCMOS15 (10 mA)	500	500	Mbps
LVCMOS12 (8 mA)	300	300	Mbps

1. Performance is achieved with  $V_{ID} \geq 200$  mV.

**Table 25 • GPIO Maximum Input Buffer Speed**

Standard	STD	-1	Unit
LVDS25/LVDS33/LCMDS25/LCMDS33	1250	1600	Mbps
RSDS25/RSDS33	800	800	Mbps
MINILVDS25/MINILVDS33	800	800	Mbps
SUBLVDS25/SUBLVDS33	800	800	Mbps
PPDS25/PPDS33	800	800	Mbps
SLVS25/SLVS33	800	800	Mbps
SLVSE15	800	800	Mbps
HCSL25/HCSL33	800	800	Mbps
BUSLVDS25	800	800	Mbps
MLVDSE25	800	800	Mbps
LVPECL33	800	800	Mbps
SSTL25I	800	800	Mbps
SSTL25II	800	800	Mbps
SSTL18I	800	800	Mbps
SSTL18II	800	800	Mbps
SSTL15I	800	1066	Mbps
SSTL15II	800	1066	Mbps
HSTL15I	800	900	Mbps
HSTL15II	800	900	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
PCI	500	500	Mbps
LTTL33 (20 mA)	500	500	Mbps
LVCMOS33 (20 mA)	500	500	Mbps
LVCMOS25 (16 mA)	500	500	Mbps

Standard	STD	-1	Unit
LVC MOS12 (8 mA)	250	300	Mbps

**Table 27 • GPIO Maximum Output Buffer Speed**

Standard	STD	-1	Unit
LVDS25/LCMDS25	1250	1250	Mbps
LVDS33/LCMDS33	1250	1600	Mbps
RS DS25	800	800	Mbps
MINILVDS25	800	800	Mbps
SUBLVDS25	800	800	Mbps
PP DS25	800	800	Mbps
SLVSE15	500	500	Mbps
BUSLVDSE25	500	500	Mbps
MLVDSE25	500	500	Mbps
LVPECL E33	500	500	Mbps
SSTL25I	800	800	Mbps
SSTL25II	800	800	Mbps
SSTL25I (differential)	800	800	Mbps
SSTL25II (differential)	800	800	Mbps
SSTL18I	800	800	Mbps
SSTL18II	800	800	Mbps
SSTL18I (differential)	800	800	Mbps
SSTL18II (differential)	800	800	Mbps
SSTL15I	800	1066	Mbps
SSTL15II	800	1066	Mbps
SSTL15I (differential)	800	1066	Mbps
SSTL15II (differential)	800	1066	Mbps
HSTL15I	900	900	Mbps
HSTL15II	900	900	Mbps
HSTL15I (differential)	900	900	Mbps
HSTL15II (differential)	900	900	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
HSUL18I (differential)	400	400	Mbps
HSUL18II (differential)	400	400	Mbps
PCI	500	500	Mbps
LV TTL33 (20 mA)	500	500	Mbps
LVC MOS33 (20 mA)	500	500	Mbps
LVC MOS25 (16 mA)	500	500	Mbps
LVC MOS18 (12 mA)	500	500	Mbps
LVC MOS15 (10 mA)	500	500	Mbps
LVC MOS12 (8 mA)	250	300	Mbps
MIPIE25	500	500	Mbps

Parameter	Symbol	V <sub>DD</sub> = 1.0 V STD	V <sub>DD</sub> = 1.0 V –1	V <sub>DD</sub> = 1.05 V STD	V <sub>DD</sub> = 1.05 V –1	Unit	Condition
Regional clock duty cycle distortion	T <sub>DCDR</sub>	120	120	120	120	ps	At 250 MHz

The following table provides clocking specifications from –40 °C to 100 °C.

**Table 36 • High-Speed I/O Clock Characteristics (–40 °C to 100 °C)**

Parameter	Symbol	V <sub>DD</sub> = 1.0 V STD	V <sub>DD</sub> = 1.0 V –1	V <sub>DD</sub> = 1.05 V STD	V <sub>DD</sub> = 1.05 V –1	Unit	Condition
High-speed I/O clock F <sub>MAX</sub>	F <sub>MAXB</sub>	1000	1250	1000	1250	MHz	HSIO and GPIO
High-speed I/O clock skew <sup>1</sup>	F <sub>SKEWB</sub>	30	20	30	20	ps	HSIO without bridging
	F <sub>SKEWB</sub>	600	500	600	500	ps	HSIO with bridging
	F <sub>SKEWB</sub>	45	35	45	35	ps	GPIO without bridging
	F <sub>SKEWB</sub>	75	60	75	60	ps	GPIO with bridging
High-speed I/O clock duty cycle distortion <sup>2</sup>	T <sub>DCB</sub>	90	90	90	90	ps	HSIO without bridging
	T <sub>DCB</sub>	115	115	115	115	ps	HSIO with bridging
	T <sub>DCB</sub>	90	90	90	90	ps	GPIO without bridging
	T <sub>DCB</sub>	115	115	115	115	ps	GPIO with bridging

1. F<sub>SKEWB</sub> is the worst-case clock-tree skew observable between sequential I/O elements. Clock-tree skew is significantly smaller at I/O registers close to each other and fed by the same or adjacent clock-tree branches. Use the Microsemi Timing Analyzer tool to evaluate clock skew specific to the design.
2. Parameters listed in this table correspond to the worst-case duty cycle distortion observable at the I/O flip flops. IBIS should be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times for any I/O standard.

## 7.2.2 PLL

The following table provides information about PLL.

**Table 37 • PLL Electrical Characteristics**

Parameter	Symbol	Min	Typ	Max	Unit
Input clock frequency (integer mode)	F <sub>INI</sub>	1		1250	MHz
Input clock frequency (fractional mode)	F <sub>INF</sub>	10		1250	MHz
Minimum reference or feedback pulse width <sup>1</sup>	F <sub>INPULSE</sub>	200			ps
Frequency at the Frequency Phase Detector (PFD) (integer mode)	F <sub>PHDETI</sub>	1		312	MHz
Frequency at the PFD (fractional mode)	F <sub>PHDETF</sub>	10	50	125	MHz
Allowable input duty cycle	F <sub>INDUTY</sub>	25		75	%

Parameter	Symbol	Min	Typ	Max	Unit
Operating current ( $V_{DD1S}$ )	$RC_{SCVPP}$			0.1	$\mu A$
Operating current ( $V_{DD}$ )	$RC_{SCVDD}$			60.7	$\mu A$

### 7.3.2 SRAM Blocks

The following tables describe the LSRAM blocks' performance.

**Table 43 • LSRAM Performance Industrial Temperature Range (−40 °C to 100 °C)**

Parameter	V <sub>DD</sub> = 1.0 V – STD	V <sub>DD</sub> = 1.0 V – 1	V <sub>DD</sub> = 1.05 V – STD	V <sub>DD</sub> = 1.05 V – 1	Unit	Condition
Operating frequency	343	428	343	428	MHz	Two-port, all supported widths, pipelined, simple-write, and write-feed-through
	309	428	309	428	MHz	Two-port, all supported widths, non-pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Dual-port, all supported widths, pipelined, simple-write, and write-feed-through
	309	428	309	428	MHz	Dual-port, all supported widths, non-pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Two-port pipelined ECC mode, pipelined, simple-write, and write-feed-through
	279	295	279	295	MHz	Two-port non-pipelined ECC mode, pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Two-port pipelined ECC mode, non-pipelined, simple-write, and write-feed-through
	196	285	196	285	MHz	Two-port non-pipelined ECC mode, non-pipelined, simple-write, and write-feed-through
	274	285	274	285	MHz	Two-port, all supported widths, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port, all supported widths, non-pipelined, and read-before-write
	274	285	274	285	MHz	Dual-port, all supported widths, pipelined, and read-before-write
	274	285	274	285	MHz	Dual-port, all supported widths, non-pipelined, and read-before-write
	274	285	274	285	MHz	Two-port pipelined ECC mode, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port non-pipelined ECC mode, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port pipelined ECC mode, non-pipelined, and read-before-write
	193	285	193	285	MHz	Two-port non-pipelined ECC mode, non-pipelined, and read-before-write

Parameter	Symbol	STD Min	STD Typ	STD Max	-1 Min	-1 Typ	-1 Max	Unit
Reference clock input rate <sup>1, 2, 3</sup>	$F_{XCVREFCLKMAX}$ CASCADE	20		156	20		156	MHz
Reference clock rate at the PFD <sup>4</sup>	$F_{TXREFCLKPFD}$	20		156	20		156	MHz
Reference clock rate recommended at the PFD for Tx rates 10 Gbps and above <sup>4</sup>	$F_{TXREFCLKPFD10G}$	75		156	75		156	MHz
Tx reference clock phase noise requirements to meet jitter specifications (156 MHz clock at reference clock input) <sup>5</sup>	$F_{TXREFPN}$				-110		-110	dBc /Hz
Phase noise at 10 KHz	$F_{TXREFPN}$				-110		-110	dBc /Hz
Phase noise at 100 KHz	$F_{TXREFPN}$				-115		-115	dBc /Hz
Phase noise at 1 MHz	$F_{TXREFPN}$				-135		-135	dBc /Hz
Reference clock input rise time (10%–90%)	$T_{REFRISE}$		200	500		200	500	ps
Reference clock input fall time (90%–10%)	$T_{REFFALL}$		200	500		200	500	ps
Reference clock duty cycle	$T_{REFDUTY}$	40		60	40		60	%
Spread spectrum modulation spread <sup>6</sup>	Mod_Spread	0.1		3.1	0.1		3.1	%
Spread spectrum modulation frequency <sup>7</sup>	Mod_Freq	TxREF CLKPFD/ (128)	32	TxREF CLKPFD/ (128*63)	32	TxREF CLKPFD/ (128)		KHz

1. See the maximum reference clock rate allowed per input buffer standard.
2. The minimum value applies to this clock when used as an XCVR reference clock. It does not apply when used as a non-XCVR input buffer (DC input allowed).
3. Cascaded reference clock.
4. After reference clock input divider.
5. Required maximum phase noise is scaled based on actual  $F_{TxRefClkPFD}$  value by  $20 \times \log_{10} (TxRefClkPFD / 156 \text{ MHz})$ . It is assumed that the reference clock divider of 4 is used for these calculations to always meet the maximum PFD frequency specification.
6. Programmable capability for depth of down-spread or center-spread modulation.
7. Programmable modulation rate based on the modulation divider setting (1 to 63).

### 7.4.3

### Transceiver Reference Clock I/O Standards

The following table describes the differential I/O standards supported as transceiver reference clocks.

**Table 48 • Transceiver Differential Reference Clock I/O Standards**

I/O Standard	Comment
LVDS25	For DC input levels, see table <a href="#">Differential DC Input and Output Levels</a> .
HCSL25 (for PCIe)	

**Note:** The transceiver reference clock differential receiver supports V<sub>CM</sub> common mode.

#### 7.4.4 Transceiver Interface Performance

The following table describes the single-ended I/O standards supported as transceiver reference clocks.

**Table 49 • Transceiver Single-Ended Reference Clock I/O Standards**

I/O Standard	Comment
LVCMS25	For DC input levels, see table <a href="#">DC Input and Output Levels</a> .

#### 7.4.5 Transmitter Performance

The following tables describe performance of the transmitter.

**Table 50 • Transceiver Reference Clock Input Termination**

Parameter	Symbol	Min	Typ	Max	Unit
Single-ended termination	RefTerm	50		$\Omega$	
Single-ended termination	RefTerm	75		$\Omega$	
Single-ended termination	RefTerm	150		$\Omega$	
Differential termination	RefDiffTerm	115 <sup>1</sup>		$\Omega$	
Power-up termination		>50K		$\Omega$	

1. Measured at V<sub>CM</sub>= 1.2 V and VID= 350 mV.

**Note:** All pull-ups are disabled at power-up to allow hot plug capability.

**Table 51 • PolarFire Transceiver User Interface Clocks**

Parameter	Modes <sup>1</sup>	STD Min	STD Max	-1 Min	-1 Max	Unit
Transceiver TX_CLK range (non-deterministic PCS mode with global or regional fabric clocks)	8-bit, max data rate = 1.6 Gbps	200	200	MHz		
	10-bit, max data rate = 1.6 Gbps	160	160	MHz		
	16-bit, max data rate = 4.8 Gbps	300	300	MHz		
	20-bit, max data rate = 6.0 Gbps	300	300	MHz		
	32-bit, max data rate = 10.3125 Gbps (-STD) / 12.7 Gbps (-1) <sup>1</sup>	325	325	MHz		
	40-bit, max data rate = 10.3125 Gbps (-STD) / 12.7 Gbps (-1) <sup>1</sup>	260	320	MHz		
	64-bit, max data rate = 10.3125 Gbps (-STD) / 12.7 Gbps (-1) <sup>1</sup>	165	160	MHz		
	80-bit, max data rate = 10.3125 Gbps(-STD) / 12.7 Gbps (-1) <sup>1</sup>	130	130	MHz		
	Fabric pipe mode 32-bit, max data rate = 6.0 Gbps	150	150	MHz		
	8-bit, max data rate = 1.6 Gbps	200	200	MHz		

5. Improved jitter characteristics for a specific industry standard are possible in many cases due to improved reference clock or higher V<sub>CO</sub> rate used.
6. Tx jitter is specified with all transmitters on the device enabled, a 10–12-bit error rate (BER) and Tx data pattern of PRBS7.
7. From the PMA mode, the TX\_ELEC\_IDLE port to the XVCN TXP/N pins.  
FTxRefClk = 75 MHz with typical settings.  
For data rates greater than 10.3125 Gbps, VDDA must be set to 1.05 V mode. See supply tolerance in the section [Recommended Operating Conditions \(see page 6\)](#). (see page 6)

## 7.4.6 Receiver Performance

The following table describes performance of the receiver.

**Table 53 • PolarFire Transceiver Receiver Characteristics**

Parameter	Symbol	Min	Typ	Max	Unit	Condition
Input voltage range	V <sub>IN</sub>	0		V <sub>DDA</sub> + 0.3	V	
Differential peak-to-peak amplitude	V <sub>IDPP</sub>	140		1250	mV	
Differential termination	V <sub>ITERM</sub>	85			Ω	
	V <sub>ITERM</sub>	100			Ω	
	V <sub>ITERM</sub>	150			Ω	
Common mode voltage	V <sub>ICMDC</sub> <sup>1</sup>	0.7 × V <sub>DDA</sub>		0.9 × V <sub>DDA</sub>	V	DC coupled
Exit electrical idle detection time	T <sub>EIDET</sub>	50	100		ns	
Run length of consecutive identical digits (CID)	C <sub>ID</sub>		200		UI	
CDR PPM tolerance <sup>2</sup>	C <sub>DRPPM</sub>		1.15		% UI	
CDR lock-to-data time	T <sub>LTD</sub>				CDR <sub>REFCLK</sub>	
					UI	
CDR lock-to-ref time	T <sub>LTF</sub>				CDR <sub>REFCLK</sub>	
					UI	
Loss-of-signal detect (Peak Detect Range setting = high) <sup>9</sup>	V <sub>DETLHIGH</sub>				mV	Setting = 1
	V <sub>DETLHIGH</sub>				mV	Setting = 2
	V <sub>DETLHIGH</sub>				mV	Setting = 3
	V <sub>DETLHIGH</sub>				mV	Setting = 4
	V <sub>DETLHIGH</sub>				mV	Setting = 5
	V <sub>DETLHIGH</sub>				mV	Setting = 6
	V <sub>DETLHIGH</sub>				mV	Setting = 7
Loss-of-signal detect (Peak Detect Range setting = low) <sup>9</sup>	V <sub>DETLOW</sub>	65	175		mV	Setting = PCIe <sup>3,7</sup>
	V <sub>DETLOW</sub>	95	190		mV	Setting = SATA <sup>4,8</sup>
	V <sub>DETLOW</sub>	75	170		mV	Setting = 1
	V <sub>DETLOW</sub>	95	185		mV	Setting = 2
	V <sub>DETLOW</sub>	100	190		mV	Setting = 3
	V <sub>DETLOW</sub>	140	210		mV	Setting = 4
	V <sub>DETLOW</sub>	155	240		mV	Setting = 5
	V <sub>DETLOW</sub>	165	245		mV	Setting = 6
	V <sub>DETLOW</sub>	170	250		mV	Setting = 7
Sinusoidal jitter tolerance	T <sub>SJTOL</sub>				UI	>8.5 Gbps – 12.7 Gbps <sup>5,10</sup>

**Table 55 • PCI Express Gen2**

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	5.0 Gbps	0.35		UI
Receiver jitter tolerance	5.0 Gbps	0.4		UI

**Note:** With add-in card as specified in PCI Express CEM Rev 2.0.

### 7.5.2 Interlaken

The following table describes Interlaken.

**Table 56 • Interlaken**

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	6.375 Gbps	0.3		UI
	10.3125 Gbps	0.3		UI
	12.7 Gbps <sup>1</sup>			UI
Receiver jitter tolerance	6.375 Gbps	0.6		UI
	10.3125 Gbps	0.65		UI
	12.7 Gbps <sup>1</sup>			UI

- For data rates greater than 10.3125 Gbps, VDDA must be set to 1.05 V mode. See supply tolerance in the section [Recommended Operating Conditions \(see page 6\)](#).

### 7.5.3 10GbE (10GBASE-R, and 10GBASE-KR)

The following table describes 10GbE (10GBASE-R).

**Table 57 • 10GbE (10GBASE-R)**

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	10.3125 Gbps	0.28		UI
Receiver jitter tolerance	10.3125 Gbps	0.7		UI

The following table describes 10GbE (10GBASE-KR).

**Table 58 • 10GbE (10GBASE-KR)**

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter	10.3125 Gbps			UI
Receiver jitter tolerance	10.3125 Gbps			UI

The following table describes 10GbE (XAUI).

**Table 59 • 10GbE (XAUI)**

Parameter	Data Rate	Min	Max	Unit
Total transmit jitter (near end)	3.125 Gbps	0.35		UI
Total transmit jitter (far end)		0.55		UI
Receiver jitter tolerance	3.125 Gbps	0.65		UI

The following table describes 10GbE (RXAUI).

### 7.6.3 FPGA Bitstream Sizes

The following table describes FPGA bitstream sizes.

**Table 72 • Initialization Client Sizes**

Device	Plaintext	Ciphertext
MPF100T, TL, TS, TLS		
MPF200T, TL, TS, TLS	2916 KB	3006 KB
MPF300T, TL, TS, TLS	4265 KB	4403 KB
MPF500T, TL, TS, TLS		

**Note:** Worst case initializing all fabric LSRAM, USRAM, and UPROM.

**Table 73 • Bitstream Sizes**

File	Devices	FPGA	Security	SNVM (all pages)	FPGA+ SNVM	FPGA+ Sec	SNVM+ Sec	FPGA+ SNVM+ Sec
SPI	MPF100T, TL, TS, TLS							
DAT	MPF100T, TL, TS, TLS							
SPI	MPF200T, TL, TS, TLS	5.9 MB	3.4 KB	59.7 KB	5.9 MB	5.9 MB	62.2 KB	6.0 MB
DAT	MPF200T, TL, TS, TLS	5.9 MB	7.3 KB	61.2 KB	6.0 MB	5.9 MB	66.3 KB	6.0 MB
SPI	MPF300T, TL, TS, TLS	9.3 MB	3.5 KB	59.7 KB	9.6 MB	9.5 MB	62.2 KB	9.6 MB
DAT	MPF300T, TL, TS, TLS	9.3 MB	7.6 KB	61.2 KB	9.6 MB	9.5 MB	66.3 KB	9.6 MB
SPI	MPF500T, TL, TS, TLS							
DAT	MPF500T, TL, TS, TLS							

### 7.6.4 Digest Cycles

Digests verify the integrity of the programmed non-volatile data. Digests are a cryptographic hash of various data areas. Any digest that reports back an error raises the digest tamper flag.

**Table 74 • Maximum Number of Digest Cycles**

Retention Since Programmed (N = Number Digests During that Time) <sup>1</sup>										
Digest $T_J$	Storage and Operating $T_J$	N $\leq 300$	N = 500	N = 1000	N = 1500	N = 2000	N = 4000	N = 6000	Unit	Retention
-40 to 100	-40 to 100	20 × LF	17 × LF	12 × LF	10 × LF	8 × LF	4 × LF	2 × LF	°C	Years
-40 to 100	0 to 100	20 × LF	17 × LF	12 × LF	10 × LF	8 × LF	4 × LF	2 × LF	°C	Years
-40 to 85	-40 to 85	20 × LF	20 × LF	20 × LF	20 × LF	16 × LF	8 × LF	4 × LF	°C	Years
-40 to 55	-40 to 55	20 × LF	20 × LF	20 × LF	20 × LF	20 × LF	20 × LF	20 × LF	°C	Years

1. LF = Lifetime factor as defined by the number of programming cycles the device has seen under the conditions listed in the following table.

Parameter	Typ	Max	Unit	Conditions
Time to destroy data in non-volatile memory (recoverable) <sup>1,3</sup>			ms	One iteration of scrubbing
Time to destroy data in non-volatile memory (non-recoverable) <sup>1,4</sup>			ms	One iteration of scrubbing
Time to scrub the fabric data <sup>1</sup>			s	Full scrubbing
Time to scrub the pNVM data (like new) <sup>1,2</sup>			s	Full scrubbing
Time to scrub the pNVM data (recoverable) <sup>1,3</sup>			s	Full scrubbing
Time to scrub the fabric data pNVM data (non-recoverable) <sup>1,4</sup>			s	Full scrubbing
Time to verify <sup>5</sup>			s	

1. Total completion time after interning zeroization.
2. Like new mode—zeroizes user design security setting and sNVM content.
3. Recoverable mode—zeroizes user design security setting, sNVM and factory keys.
4. Non-recoverable mode—zeroizes user design security setting, sNVM and factory keys, and factory data required for programming.
5. Time to verify after scrubbing completes.

**Table 79 • Zeroization Times for MPF300T, TL, TS, and TLS Devices**

Parameter	Typ	Max	Unit	Conditions
Time to enter zeroization			ms	Zip flag set
Time to destroy the fabric data <sup>1</sup>			ms	Data erased
Time to destroy data in non-volatile memory (like new) <sup>1,2</sup>			ms	One iteration of scrubbing
Time to destroy data in non-volatile memory (recoverable) <sup>1,3</sup>			ms	One iteration of scrubbing
Time to destroy data in non-volatile memory (non-recoverable) <sup>1,4</sup>			ms	One iteration of scrubbing
Time to scrub the fabric data <sup>1</sup>			s	Full scrubbing
Time to scrub the pNVM data (like new) <sup>1,2</sup>			s	Full scrubbing
Time to scrub the pNVM data (recoverable) <sup>1,3</sup>			s	Full scrubbing
Time to scrub the fabric data pNVM data (non-recoverable) <sup>1,4</sup>			s	Full scrubbing
Time to verify <sup>5</sup>			s	

1. Total completion time after interning zeroization.
2. Like new mode—zeroizes user design security setting and sNVM content.
3. Recoverable mode—zeroizes user design security setting, sNVM and factory keys.
4. Non-recoverable mode—zeroizes user design security setting, sNVM and factory keys, and factory data required for programming.
5. Time to verify after scrubbing completes.

**Table 80 • Zeroization Times for MPF500T, TL, TS, and TLS Devices**

Parameter	Typ	Max	Unit	Conditions
Time to enter zeroization			ms	Zip flag set
Time to destroy the fabric data <sup>1</sup>			ms	Data erased
Time to destroy data in non-volatile memory (like new) <sup>1,2</sup>			ms	One iteration of scrubbing
Time to destroy data in non-volatile memory (recoverable) <sup>1,3</sup>			ms	One iteration of scrubbing

Parameter	Type	Max	Unit	Conditions
Time to destroy data in non-volatile memory (non-recoverable) <sup>1,4</sup>		ms		One iteration of scrubbing
Time to scrub the fabric data <sup>1</sup>		s		Full scrubbing
Time to scrub the pNVM data (like new) <sup>1,2</sup>		s		Full scrubbing
Time to scrub the pNVM data (recoverable) <sup>1,3</sup>		s		Full scrubbing
Time to scrub the fabric data pNVM data (non-recoverable) <sup>1</sup>		s		Full scrubbing
Time to verify <sup>5</sup>		s		

1. Total completion time after entering zeroization.
2. Like new mode—zeroizes user design security setting and sNVM content.
3. Recoverable mode—zeroizes user design security setting, sNVM and factory keys.
4. Non-recoverable mode—zeroizes user design security setting, sNVM and factory keys, and factory data required for programming.
5. Time to verify after scrubbing completes.

## 7.6.7 Verify Time

The following tables describe verify time.

**Table 81 • Standalone Fabric Verify Times**

Parameter	Devices	Max	Unit
Standalone verification over JTAG	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	53 <sup>1</sup>	s
	MPF300T, TL, TS, TLS	90 <sup>1</sup>	s
	MPF500T, TL, TS, TLS		s
Standalone verification over SPI	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	37 <sup>2</sup>	s
	MPF300T, TL, TS, TLS	55 <sup>2</sup>	s
	MPF500T, TL, TS, TLS		s

1. Programmer: FlashPro5, TCK 10 MHz; PC configuration: Intel i7 at 3.6 GHz, 32 GB RAM, Windows 10.
2. SmartFusion2 with MSS running at 100 MHz, MSS\_SPI\_0 port running at 6.67 MHz. DirectC version 4.1.

**Notes:**

- Standalone verify is limited to 2,000 total device hours over the industrial –40 °C to 100 °C temperature.
- Use the digest system service, for verify device time more than 2,000 hours.
- Standalone verify checks the programming margin on both the P and N gates of the push-pull cell.
- Digest checks only the P side of the push-pull gate. However, the push-pull gates work in tandem. Digest check is recommended if users believe they will exceed the 2,000-hour verify time specification.

**Table 82 • Verify Time by Programming Hardware**

Devices	IAP	FlashPro4	FlashPro5	BP	Silicon Sculptor	Units
MPF100T, TL, TS, TLS						
MPF200T, TL, TS, TLS	9	67	53			s
MPF300T, TL, TS, TLS	14	95	90			s

**Table 101 • Cold and Warm Boot**

Parameter	Symbol	Min	Typ	Max	Unit	Condition
The time from $T_{FAB\_READY}$ to ready to program through JTAG/SPI-Slave		0	0	0	ms	
The time from $T_{FAB\_READY}$ to auto-update start			$T_{PUF\_OVHD}^1$	$T_{PUF\_OVHD}^1$	ms	
The time from $T_{FAB\_READY}$ to programming recovery start			$T_{PUF\_OVHD}^1$	$T_{PUF\_OVHD}^1$	ms	
The time from $T_{FAB\_READY}$ to the tamper flags being available	$T_{TAMPER\_READY}$	0	0	0	ms	
The time from $T_{FAB\_READY}$ to the Athena Crypto co-processor being available (for S devices only)	$T_{CRYPTO\_READY}$	0	0	0	ms	

1. Programming depends on the PUF to power up. Refer to  $T_{PUF\_OVHD}$  at section [Secure NVM Performance](#) (see page 58).

## 7.9.8 I/O Calibration

The following tables specify the initial I/O calibration time for the fastest and slowest supported VDDI ramp times of 0.2 ms to 50 ms, respectively. This only applies to I/O banks specified by the user to be auto-calibrated.

**Table 102 • I/O Initial Calibration Time (TCALIB)**

Ramp Time	Min (ms)	Max (ms)	Condition
0.2 ms	0.98	2.63	Applies to HSIO and GPIO banks
50 ms	41.62	62.19	Applies to HSIO and GPIO banks

### Notes:

- The user may specify any VDDI ramp time in the range specified above. The nominal initial calibration time is given by the specified VDDI ramp time plus 2 ms.
- In order for IO calibration to start, VDDI and VDDAUX of the I/O bank must be higher than the trip point levels specified in [I/O-Related Supplies](#) (see page 66).

**Table 103 • I/O Fast Recalibration Time (TRECALIB)**

I/O Type	Min (ms)	Typ (ms)	Max (ms)	Condition
GPIO bank	0.16	0.20	0.24	GPIO configured for 3.3 V operation
HSIO bank	0.20	0.25	0.30	HSIO configured for 1.8 V operation

**Note:** In order to obtain fast re-calibration, the user must assert the relevant clock request signal from the FPGA fabric to the I/O bank controller.

The following table describes the time to enter Flash\*Freeze Mode and to exit Flash\*Freeze mode.

ECDSA SigVer, P-384/SHA-384	1024 8K	6421841 6273510	5759 5759
Key Agreement (KAS), P-384		5039125	6514
Point Multiply, P-256 <sup>1</sup>		5176923	4482
Point Multiply, P-384 <sup>1</sup>		12043199	5319
Point Multiply, P-521 <sup>1</sup>		26887187	6698
Point Addition, P-384		3018067	5779
KeyGen (PKG), P-384		12055368	6908
Point Verification, P-384		5091	3049

1. With DPA counter measures.

**Table 120 • IFC (RSA)**

Modes	Message Size (bits)	Athena TeraFire Crypto Core Clock-Cycles	CAL Delay In CPU Clock-Cycles
Encrypt, RSA-2048, e=65537	2048	436972	8,972
Encrypt, RSA-3072, e=65537	3072	962162	12,583
Decrypt, RSA-2048 <sup>1</sup> , CRT	2048	26862392	15900
Decrypt, RSA-3072 <sup>1</sup> , CRT	3072	75153782	22015
Decrypt, RSA-4096, CRT	4096	89235615	23710
Decrypt, RSA-3072, CRT	3072	37880180	18638
SigGen, RSA-3072/SHA-384 <sup>1</sup> ,CRT, PKCS #1 V 1.5	1024 8K	75197644 75213653	20032 19303
SigGen, RSA-3072/SHA-384, PKCS #1, V 1.5	1024 8K	148090970 148102576	14642 13936
SigVer, RSA-3072/SHA-384, e = 65537, PKCS #1 V 1.5	1024 8K	970991 982011	12000 11769
SigVer, RSA-2048/SHA-256, e = 65537, PKCS #1 V 1.5	1024 8K	443493 453007	8436 8436
SigGen, RSA-3072/SHA-384, ANSI X9.31	1024 8K	147138254 147155896	13945 13523
SigVer, RSA-3072/SHA-384, e = 65537, ANSI X9.31	1024 8K	973269 983255	11313 11146

1. With DPA counter measures.

**Table 121 • FFC (DH)**

Modes	Message Size (bits)	Athena TeraFire Crypto Core Clock-Cycles	CAL Delay In CPU Clock-Cycles
SigGen, DSA-3072/SHA-384 <sup>1</sup>	1024 8K	27932907 27942415	13969 13501
SigGen, DSA-3072/SHA-384	1024	12086356	13602
SigVer, DSA-3072/SHA-384	1024 8K	24597916 24229420	15662 15133